



Data Sheet

Customer:	
Part No:	CLD-2821APG-11
Sample No:	
Description:	0.28 inch 2 Digit Green Color
Item No:	

Customer				
Check	Inspection	Approval	Date	

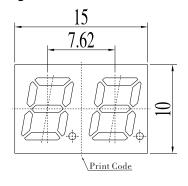


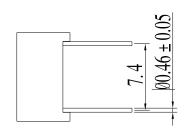


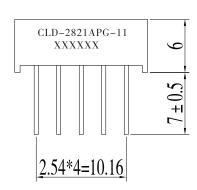
Descriptions

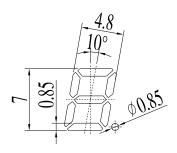
Emitting color: Pure Green
 Lens color: White Diffused
 Surface black color: Black
 Dice material: InGaN/GaN

Outline drawing



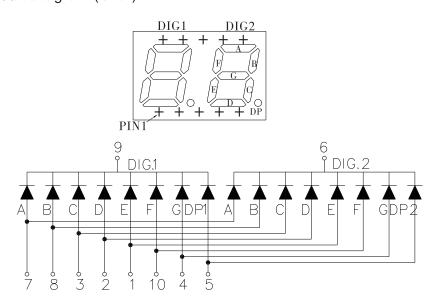






Tolerance is \pm 0.25mm unless otherwise noted , Unit=mm Pin bending \leq length*1%

Internal Circuit Diagram (C.C.)







Electrical optical characteristics ($Ta=25^{\circ}C$)

Parameter	Symbol	Pure Green			TT	m . C 1:::	
		Min	Тур	Max	Unit	Test Condition	
Forward Voltage	\mathbf{V}_{F}		3.2	3.6	V	IF=20mA	
Luminous Intensity	Iv	13.7	26.6		mcd	IF=10mA	
Peak Wavelength	λP		525		nm	IF=20mA	
Dominant Wavelength	λd		520		nm	IF=20mA	
Spectral Line half–width	Δλ		30		nm	IF=20mA	
Reverse Leakage Current	I_R			50	μA	VR=5V	

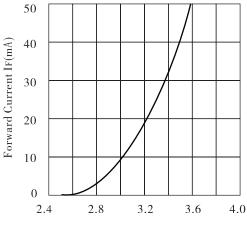
Absolute Maximum Parameters(Ta=25°C)

Parameter	Symbol	Condition	Rating	Unit
Power Dissipation	PD		120	mW
Reverse Voltage	$ m V_{R}$		5	V
Forward Average Current	\mathbf{I}_{F}		30	mA
Temperature Cofficient	I/C		0.4	mA/°C
Pulse Current	IFP	Duty=1/10,1kHz	100	mA
Operating Temperature Range	Topr		−25 ~ +85	$^{\circ}$
Storage Temperature Range	Tstg		-30 ~ +100	$^{\circ}$
Soldering Condition	Tsd		260℃/5sec	${\mathcal C}$

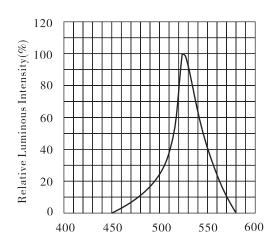




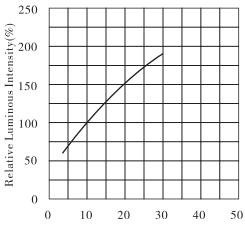
Typical Electro-Optical characteristic curves ($Ta=25^{\circ}C$)



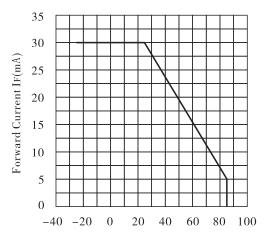




Peak Wavelength $\lambda P(nm)$



Forward Current IF (mA)



Ambient Temperature Ta(°C)





Reliability test conditions

Test Item	Test Condition	Result	Judgment criteria		
Consecutive operating life test	IF=20mA, T=25°C, t=168h	0/12			
High temperature storage life test	T=100℃, t=168h	0/12			
Low temperature storage life test	T=−25°C, t=168h	0/12	Forward Voltage VF(V)= Upper Limit × 1.2		
high Temperature humidity storage life test	T=85 ± 2°C, RH=85% ± 3, t=168h	0/12	Reverse Leakage Current IR(μA)=Upper Limit × 2.0 Luminous Intensity Iv		
Temperature cycle test	-25°C~25°C~100°C, 30min 5min 30min 10cycles	0/12	(mcd)=Lower Limit × 0.7		
Thermal shock test	100℃ 0℃ 5min 5min 20 cycles	0/12			
Soldering heat test	$T=260 \pm 5$ °C, $t=10s \pm 1s$	0/12			
Solderability test	$T=230 \pm 5$ °C, $t=5s \pm 0.5s$	0/12	Steeped Part≥95%		
Fall test	h=100cm, Free fall, 3times	0/12			
Terminal strength test	W=9.8N, $t=30 \pm 5s$	0/12	Intact		
Lead Bending test	W=4.9N, 2times	0/12			